36Mb NtRAMTM Specification

100 TQFP with Pb / Pb-Free (RoHS compliant)

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Document Title

1Mx36 & 2Mx18-Bit Flow Through NtRAM™

Revision History

Rev. No	. <u>History</u>	<u>Draft Date</u>	<u>Remark</u>
0.0	1. Initial document.	Jan. 26. 2006	Advance
0.1	1. Add the overshoot timing	Feb. 16 2006	Preliminary
0.2	1. Change ordering information	Apr. 04. 2006	Preliminary
1.0	1. Finalize the datasheet	July.14. 2006	Final
1.1	1. Change Access time 7.5ns to 6.5ns	June. 10. 2007	Final



1Mx36 & 2Mx18 Flow-Through NtRAMTM

36Mb NtRAM (Flow Through) Ordering Information

Org.	VDD (V)	Speed (ns)	Access Time (ns)	Part Number	RoHS Avail.
2Mx18	3.3/2.5	8.5	6.5	K7M321835C-P(Q) ¹ C(I) ² 65	\checkmark
1Mx36	3.3/2.5	8.5	6.5	K7M323635C-P(Q)1C(I)265	√

Note 1. P(Q) [Package type] : P-Pb Free, Q-Pb

2. C(I) [Operating Temperature] : C-Commercial, I-Industrial



1Mx36 & 2Mx18-Bit Flow Through NtRAM™

FEATURES

- V_{DD}= 2.5 or 3.3V +/- 5% Power Supply.
- Byte Writable Function.
- · Enable clock and suspend operation.
- · Single READ/WRITE control pin.
- · Self-Timed Write Cycle.
- Three Chip Enable for simple depth expansion with no data contention.
- A interleaved burst or a linear burst mode.
- · Asynchronous output enable control.
- · Power Down mode.
- TTL-Level Three-State Outputs.
- 100-TQFP-1420A (Lead and Lead free package)
- Operating in commeical and industrial temperature range.

FAST ACCESS TIMES

Parameter	Sym.	-65	Unit
Cycle Time	tcyc	7.5	ns
Clock Access Time	tcp	6.5	ns
Output Enable Access	toe	3.5	ns

GENERAL DESCRIPTION

The K7M323635C and K7M321835C are 37,748,736-bits Synchronous Static SRAMs.

The NtRAM™, or No Turnaround Random Access Memory utilizes all bandwidth in any combination of operating cycles.

Address, data inputs, and all control signals except output enable and linear burst order are synchronized to input clock. Burst order control must be tied "High or Low".

Asynchronous inputs include the sleep mode enable(ZZ).

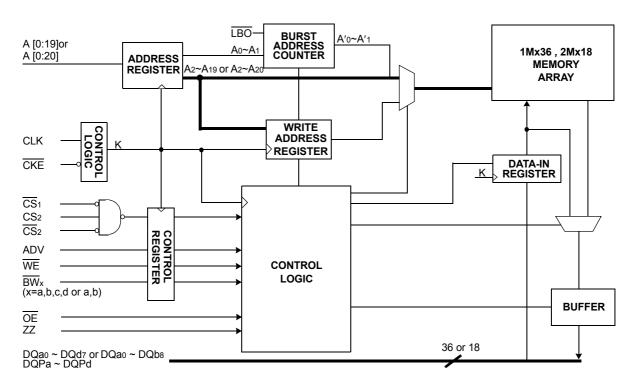
Output Enable controls the outputs at any given time.

Write cycles are internally self-timed and initiated by the rising edge of the clock input. This feature eliminates complex off-chip write pulse generation

and provides increased timing flexibility for incoming signals. For read cycles, Flow-Through SRAM allows output data to simply flow freely from the memory array.

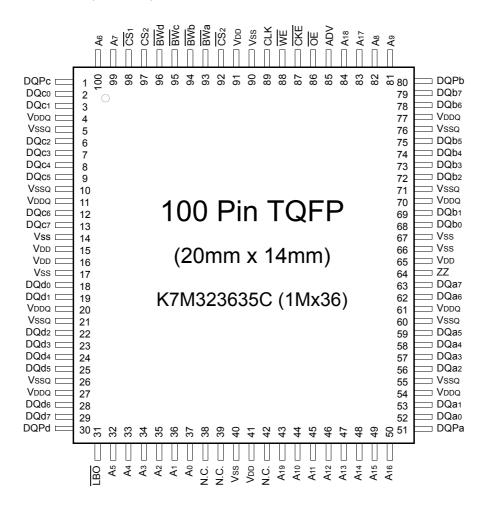
The K7M323635C and K7M321835C are implemented with SAMSUNG's high performance CMOS technology and is available in 100pin TQFP packages. Multiple power and ground pins minimize ground bounce.

LOGIC BLOCK DIAGRAM





PIN CONFIGURATION(TOP VIEW)



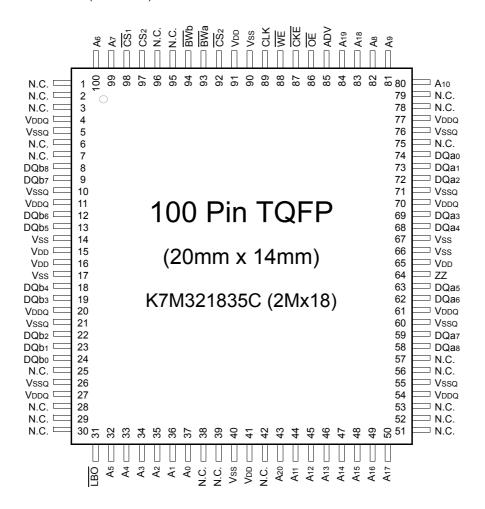
PIN NAME

SYMBOL	PIN NAME	TQFP PIN NO.	SYMBOL	PIN NAME	TQFP PIN NO.
A0 - A19	Address Inputs	32,33,34,35,36,37,43	Vdd	Power Supply(+3.3V)	15,16,41,65,91
		4445,46,47,48,49,50,	Vss	Ground	14,17,40,66,67,90
		81,82,83,84,99,100			
ADV	Address Advance/Load	85	N.C.	No Connect	38,39,42
WE	Read/Write Control Input	88			
CLK	Clock	89	DQao~a7	Data Inputs/Outputs	52,53,56,57,58,59,62,63
CKE	Clock Enable	87	DQbo~b7	Data Inputs/Outputs	68,69,72,73,74,75,78,79
CS ₁	Chip Select	98	DQco~c7	Data Inputs/Outputs	2,3,6,7,8,9,12,13
CS ₂	Chip Select	97	DQdo~d7	Data Inputs/Outputs	18,19,22,23,24,25,28,29
CS ₂	Chip Select	92	DQPa~Pd	Data Inputs/Outputs	51,80,1,30
BWx(x=a,b,c,d)	Byte Write Inputs	93,94,95,96			
OE	Output Enable	86	VDDQ	Output Power Supply	4,11,20,27,54,61,70,77
ZZ	Power Sleep Mode	64		(2.5V or 3.3V)	
LBO	Burst Mode Control	31	Vssq	Output Ground	5,10,21,26,55,60,71,76

Notes: 1. Ao and A1 are the two least significant bits(LSB) of the address field and set the internal burst counter if burst is desired.



PIN CONFIGURATION (TOP VIEW)



PIN NAME

SYMBOL	PIN NAME	TQFP PIN NO.	SYMBOL	PIN NAME	TQFP PIN NO.
A0 - A20	Address Inputs	32,33,34,35,36,37,43	VDD	Power Supply(+3.3V)	15,16,41,65,91
		44,45,46,47,48,49,50,	Vss	Ground	14,17,40,66,67,90
		80,81,82,83,84,99,100			
ADV	Address Advance/Load	85	N.C.	No Connect	1,2,3,6,7,25,28,29,30,
WE	Read/Write Control Input	88			38,39,42,51,52,53,
CLK	Clock	89			56,57,75,78,79,95,96
CKE CS ₁	Clock Enable	87			
CS ₁	Chip Select	98	DQao~a8	Data Inputs/Outputs	58,59,62,63,68,69,72,73,74
CS ₂	Chip Select	97	DQbo~b8	Data Inputs/Outputs	8,9,12,13,18,19,22,23,24
CS ₂	Chip Select	92			
$\overline{BW}x(x=a,b)$	Byte Write Inputs	93,94			
ŌĒ	Output Enable	86	VDDQ	Output Power Supply	4,11,20,27,54,61,70,77
ZZ	Power Sleep Mode	64		(2.5V or 3.3V)	
LBO	Burst Mode Control	31	Vssq	Output Ground	5,10,21,26,55,60,71,76

Notes: 1. Ao and A1 are the two least significant bits(LSB) of the address field and set the internal burst counter if burst is desired.



1Mx36 & 2Mx18 Flow-Through NtRAM™

FUNCTION DESCRIPTION

The K7M323635C and K7M321835C are $NtRAM^{TM}$ designed to sustain 100% bus bandwidth by eliminating turnaround cycle when there is transition from Read to Write, or vice versa.

All inputs (with the exception of \overline{OE} , \overline{LBO} and ZZ) are synchronized to rising clock edges.

All read, write and deselect cycles are initiated by the ADV input. Subsequent burst addresses can be internally generated by the burst advance pin (ADV). ADV should be driven to Low once the device has been deselected in order to load a new address for next operation.

Clock Enable($\overline{\text{CKE}}$) pin allows the operation of the chip to be suspended as long as necessary. When $\overline{\text{CKE}}$ is high, all synchronous inputs are ignored and the internal device registers will hold their previous values.

 $NtRAM^{TM}$ latches external address and initiates a cycle, when \overline{CKE} , ADV are driven to low and all three chip enables(\overline{CS}_1 , CS_2 , \overline{CS}_2) are active. Output Enable(\overline{OE}) can be used to disable the output at any given time.

Read operation is initiated when at the rising edge of the clock, the address presented to the address inputs are latched in the address register, \overline{CKE} is driven low, all three chip enables(\overline{CS}_1 , \overline{CS}_2) are active, the write enable input signals \overline{WE} are driven high, and ADV driven low. Data appears at the outputs within the same clock cycle as the address for the data. Also during read operation \overline{OE} must be driven low for the device to drive out the requested data.

Write operation occurs when $\overline{\text{WE}}$ is driven low at the rising edge of the clock. $\overline{\text{BW}}$ [d:a] can be used for byte write operation. The Flow Through NtRAMTM uses a late write cycle to utilize 100% of the bandwidth.

At the first rising edge of the clock, WE and address are registered, and the data associated with that address is required one cycle later.

Subsequent addresses are generated by ADV High for the burst access as shown below. The starting point of the burst seguence is provided by the external address. The burst address counter wraps around to its initial state upon completion.

The burst sequence is determined by the state of the $\overline{\text{LBO}}$ pin. When this pin is low, linear burst sequence is selected. And when this pin is high, Interleaved burst sequence is selected.

During normal operation, ZZ must be driven low. When ZZ is driven high, the SRAM will enter a Power Sleep Mode after 2 cycles. At this time, internal state of the SRAM is preserved. When ZZ returns to low, the SRAM normally operates after 2 cycles of wake up time.

BURST SEQUENCE TABLE

(Interleaved Burst, $\overline{\text{LBO}}$ =High)

LBO PIN	HIGH	Cas	se 1	Cas	se 2	Cas	se 3	Case 4	
LBO I III	111011	A 1	A ₀	A 1	A ₀	A 1	A ₀	A 1	A 0
Fi	rst Address	0	0	0	1	1	0	1	1
		0	1	0	0	1	1	1	0
	\downarrow	1	0	1	1	0	0	0	1
Fou	urth Address	1	1	1	0	0	1	0	0

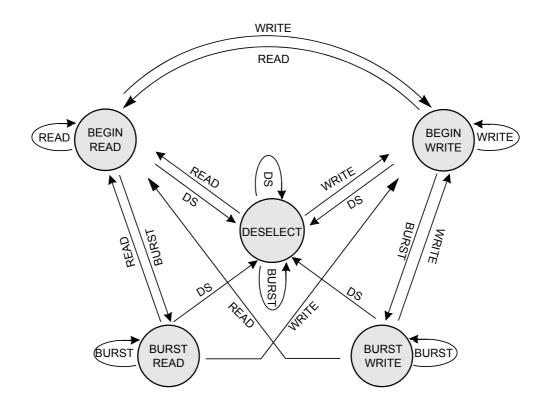
(Linear Burst, LBO=Low)

LBO PIN	LOW	LOW Case 1		Case 2		Case 3		Case 4	
LBO FIN	LOW	A 1	A ₀						
First Address		0	0	0	1	1	0	1	1
		0	1	1	0	1	1	0	0
	\downarrow	1	0	1	1	0	0	0	1
Fou	urth Address	1	1	0	0	0	1	1	0

Note: 1. LBO pin must be tied to High or Low, and Floating State must not be allowed.



STATE DIAGRAM FOR NtRAMTM



COMMAND	ACTION
DS	DESELECT
READ	BEGIN READ
WRITE	BEGIN WRITE
BURST	BEGIN READ BEGIN WRITE CONTINUE DESELECT

Notes: 1. An IGNORE CLOCK EDGE cycle is not shown is the above diagram. This is because CKE HIGH only blocks the clock(CLK) input and does not change the state of the device.

2. States change on the rising edge of the clock(CLK)



TRUTH TABLES

SYNCHRONOUS TRUTH TABLE

CS ₁	CS ₂	CS ₂	ADV	WE	BWx	OE	CKE	CLK	ADDRESS ACCESSED	OPERATION
Н	Х	Χ	L	Х	Х	Х	L	↑	N/A	Not Selected
Χ	L	Х	L	Χ	Х	Χ	L	\uparrow	N/A	Not Selected
Χ	Х	Ι	L	Χ	Х	Χ	L	\uparrow	N/A	Not Selected
Χ	Х	Х	Н	Х	Χ	Х	L		N/A	Not Selected Continue
L	Н	L	L	Н	Х	L	L	↑	External Address	Begin Burst Read Cycle
Х	Х	Х	Н	Χ	Х	L	L	↑	Next Address	Continue Burst Read Cycle
L	Н	L	L	Н	Х	Н	L	↑	External Address	NOP/Dummy Read
Х	Х	Х	Н	Χ	Х	Н	L	↑	Next Address	Dummy Read
L	Н	L	L	L	L	Х	L	↑	External Address	Begin Burst Write Cycle
Х	Х	Х	Н	Χ	L	Х	L	↑	Next Address	Continue Burst Write Cycle
L	Н	L	L	L	Н	Х	L	↑	N/A	NOP/Write Abort
Х	Х	Х	Н	Х	Н	Х	L	↑	Next Address	Write Abort
Х	Х	Х	Х	Х	Х	Х	Н	↑	Current Address	Ignore Clock

Notes: 1. X means "Don't Care". 2. The rising edge of clock is symbolized by (↑).

- 3. A continue deselect cycle can only be enterd if a deselect cycle is executed first.
- 4. WRITE = L means Write operation in WRITE TRUTH TABLE.

 WRITE = H means Read operation in WRITE TRUTH TABLE.
- 5. Operation finally depends on status of asynchronous input pins(ZZ and $\overline{\text{OE}}$).

WRITE TRUTH TABLE(x36)

WE	BWa	BWb	BWc	BWd	OPERATION
Н	X	X	X	X	READ
L	L	Н	Н	Н	WRITE BYTE a
L	Н	L	Н	Н	WRITE BYTE b
L	Н	Н	L	Н	WRITE BYTE c
L	Н	Н	Н	L	WRITE BYTE d
L	L	L	L	L	WRITE ALL BYTEs
L	Н	Н	Н	Н	WRITE ABORT/NOP

Notes: 1. X means "Don't Care".

2. All inputs in this table must meet setup and hold time around the rising edge of $\mathsf{CLK}(\uparrow)$.

WRITE TRUTH TABLE(x18)

WE	BWa	BWb	OPERATION		
Н	X	X	READ		
L	L	Н	WRITE BYTE a		
L	Н	L	WRITE BYTE b		
L	L	L	WRITE ALL BYTEs		
L	Н	Н	WRITE ABORT/NOP		

Notes: 1. X means "Don't Care".

2. All inputs in this table must meet setup and hold time around the rising edge of CLK(↑).



ASYNCHRONOUS TRUTH TABLE

Operation	ZZ	OE	I/O STATUS
Sleep Mode	Н	Χ	High-Z
-	L	L	DQ
Read	L	Н	High-Z
Write	L	Х	Din, High-Z
Deselected	L	Χ	High-Z

Notes

- 1. X means "Don't Care".
- Sleep Mode means power Sleep Mode of which stand-by current does not depend on cycle time.
- 3. Deselected means power Sleep Mode of which stand-by current depends on cycle time.

ABSOLUTE MAXIMUM RATINGS*

PARAMETER		SYMBOL	RATING	UNIT
Voltage on VDD Supply Relative to Vss	VDD	-0.3 to 4.6	V	
Voltage on Any Other Pin Relative to Vss		Vin	-0.3 to VDD+0.3	V
Power Dissipation		PD	1.6	W
Storage Temperature		Тѕтс	-65 to 150	°C
On and in a Tanana and an	Commercial	Topr	0 to 70	°C
Operating Temperature	Industrial	Topr	-40 to 85	°C
Storage Temperature Range Under Bias		TBIAS	-10 to 85	°C

^{*}Notes: Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operating sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

OPERATING CONDITIONS

PARAMETER	SYMBOL	MIN	Тур.	MAX	UNIT
Supply Voltage	V _{DD1}	2.375	2.5	2.625	V
	VDDQ1	2.375	2.5	2.625	V
	V _{DD2}	3.135	3.3	3.465	V
	VDDQ2	3.135	3.3	3.465	V
Ground	Vss	0	0	0	V

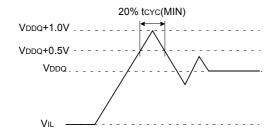
Notes: 1. The above parameters are also guaranteed at industrial temperature range.

CAPACITANCE*(TA=25°C, f=1MHz)

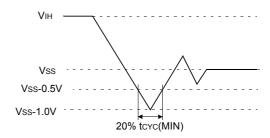
PARAMETER	SYMBOL	TEST CONDITION	MIN	MAX	UNIT
Input Capacitance	Cin	VIN=0V	-	5	pF
Output Capacitance	Соит	Vout=0V		7	pF

^{*}Note: Sampled not 100% tested.

Overshoot Timing



Undershoot Timing





^{2.} It should be VDDQ ≤ VDD

DC ELECTRICAL CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	MAX	UNIT	NOTES
Input Leakage Current(except ZZ)	lı∟	VDD=Max ; VIN=Vss to VDD	-2	+2	μΑ	
Output Leakage Current	lol	Output Disabled,	-2	+2	μΑ	
Operating Current	Icc	Device Selected, Iouτ=0mA, ZZ≤VIL , Cycle Time ≥ tcγc Min	-	310	mA	1,2
	ISB	Device deselected, Iou τ =0mA, ZZ \leq VIL, f=Max, All Inputs \leq 0.2V or \geq VDD-0.2V	-	140	mA	
Standby Current	ISB1	Device deselected, IouT=0mA, ZZ≤0.2V, f=0, All Inputs=fixed (VDD-0.2V or 0.2V)	-	110	mA	
	ISB2	Device deselected, louт=0mA, ZZ≥Vpp-0.2V, f=Max, All Inputs≤Vi⊾ or ≥ViH	-	100	mA	
Output Low Voltage(3.3V I/O)	Vol	IoL=8.0mA	-	0.4	V	
Output High Voltage(3.3V I/O)	Vон	Iон=-4.0mA	2.4	-	V	
Output Low Voltage(2.5V I/O)	Vol	IoL=1.0mA	-	0.4	V	
Output High Voltage(2.5V I/O)	Vон	Iон=-1.0mA	2.0	-	V	
Input Low Voltage(3.3V I/O)	VIL		-0.3*	0.8	V	
Input High Voltage(3.3V I/O)	ViH		2.0	VDD+0.3**	V	3
Input Low Voltage(2.5V I/O)	VIL		-0.3*	0.7	V	
Input High Voltage(2.5V I/O)	ViH		1.7	VDD+0.3**	V	3

Notes: 1. The above parameters are also guaranteed at industrial temperature range.

2. Reference AC Operating Conditions and Characteristics for input and timing.

3. Data states are all zero.

4. In Case of I/O Pins, the Max. VIH=VDDQ+0.3V.

TEST CONDITIONS

PARAMETER	VALUE
Input Pulse Level(for 3.3V I/O)	0 to 3.0V
Input Pulse Level(for 2.5V I/O)	0 to 2.5V
Input Rise and Fall Time(Measured at 20% to 80% for 3.3/2.5V I/O)	1.0V/ns
Input and Output Timing Reference Levels for 3.3V I/O	1.5V
Input and Output Timing Reference Levels for 2.5V I/O	VDDQ/2
Output Load	See Fig. 1

^{*} The above parameters are also guaranteed at industrial temperature range.

Output Load(A) Output Load(B), (for tLzC, tLzOE, tHzOE & tHzC) +3.3V for 3.3V I/O RL= 50Ω Dout /+2.5V for 2.5V I/O → VL=1.5V for 3.3V I/O 319Ω / 1667Ω VDDQ/2 for 2.5V I/O 30pF* Dout Zo=50Ω $353\Omega\,/\,1538\Omega$ 5pF*

* Including Scope and Jig Capacitance

Fig. 1



1Mx36 & 2Mx18 Flow-Through NtRAM™

AC TIMING CHARACTERISTICS

242445752	OVMDOL		LINUT	
PARAMETER	SYMBOL -	MIN	MAX	UNIT
Cycle Time	tcyc	7.5	-	ns
Clock Access Time	tcp	-	6.5	ns
Output Enable to Data Valid	toe	-	3.5	ns
Clock High to Output Low-Z	tLZC	2.5	-	ns
Output Hold from Clock High	tон	2.5	-	ns
Output Enable Low to Output Low-Z	tlzoe	0	-	ns
Output Enable High to Output High-Z	tHZOE	-	3.5	ns
Clock High to Output High-Z	tHZC	-	3.8	ns
Clock High Pulse Width	tсн	2.5	-	ns
Clock Low Pulse Width	tcL	2.5	-	ns
Address Setup to Clock High	tas	1.5	-	ns
CKE Setup to Clock High	tces	1.5	-	ns
Data Setup to Clock High	tos	1.5	-	ns
Write Setup to Clock High (WE, BWx)	tws	1.5	-	ns
Address Advance Setup to Clock High	tadvs	1.5	-	ns
Chip Select Setup to Clock High	tcss	1.5	-	ns
Address Hold from Clock High	tah	0.5	-	ns
CKE Hold from Clock High	tcen	0.5	-	ns
Data Hold from Clock High	tон	0.5	-	ns
Write Hold from Clock High (WE, BWx)	twн	0.5	-	ns
Address Advance Hold from Clock High	tadvh	0.5	-	ns
Chip Select Hold from Clock High	tcsH	0.5	-	ns
ZZ High to Power Down	tpds	2	-	cycle
ZZ Low to Power Up	tpus	2	-	cycle

It is not possible for two SRAMs on the same board to be at such different voltage and temperatue.



Notes: 1. The above parameters are also guaranteed at industrial temperature range.

2. All address inputs must meet the specified setup and hold times for all rising clock(CLK) edges when ADV is sampled low and CS is sampled.

^{2.} All address inputs must meet the specified setup and hold times for all histing clock(CLX) edges when ADV is sampled low and CS is sampled low. All other synchronous inputs must meet the specified setup and hold times whenever this device is chip selected.
3. Chip selects must be valid at each rising edge of CLX(when ADV is Low) to remain enabled.
4. A write cycle is defined by WE low having been registerd into the device at ADV Low, A Read cycle is defined by WE High with ADV Low, Both cases must meet setup and hold times.

^{5.} To avoid bus contention, At a given vlotage and temperature tLzc is more than tHzc.

The soecs as shown do not imply bus contention because tLzc is a Min. parameter that is worst case at totally different test conditions (0°C,3.465V) than tHzc, which is a Max. parameter(worst case at 70°C,3.135V)

1Mx36 & 2Mx18 Flow-Through NtRAM™

SLEEP MODE

SLEEP MODE is a low current, power-down mode in which the device is deselected and current is reduced to IsB2. The duration of SLEEP MODE is dictated by the length of time the ZZ is in a High state.

After entering SLEEP MODE, all inputs except ZZ become disabled and all outputs go to High-Z

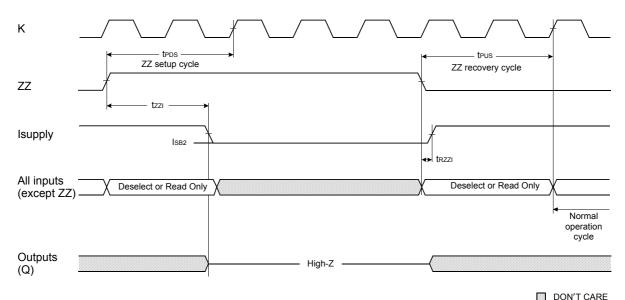
The ZZ pin is an asynchronous, active high input that causes the device to enter SLEEP MODE.

When the ZZ pin becomes a logic High, ISB2 is guaranteed after the time tzzı is met. Any operation pending when entering SLEEP MODE is not guaranteed to successful complete. Therefore, SLEEP MODE (READ or WRITE) must not be initiated until valid pending operations are completed. similarly, when exiting SLEEP MODE during tpus, only a DESELECT or READ cycle should be given while the SRAM is transitioning out of SLEEP MODE.

SLEEP MODE ELECTRICAL CHARACTERISTICS

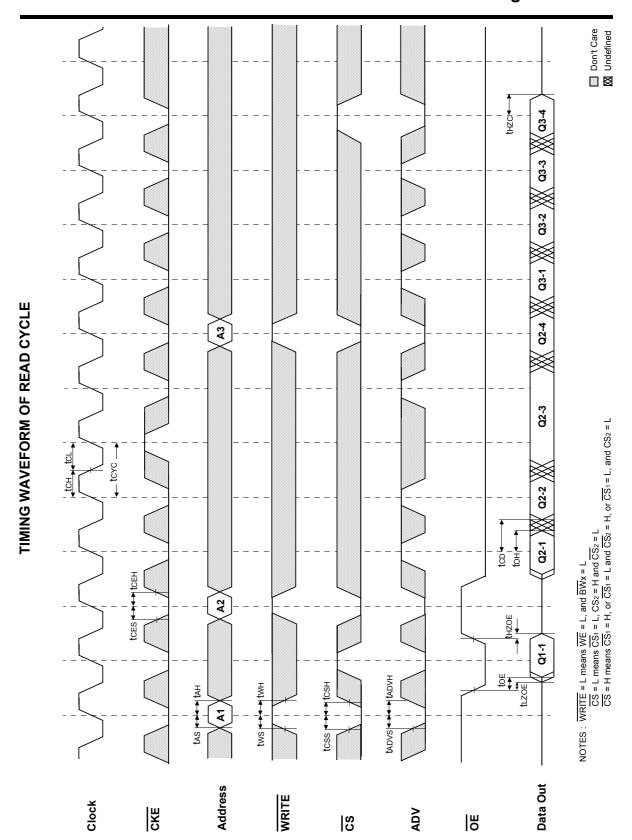
DESCRIPTION	CONDITIONS	SYMBOL	MIN	MAX	UNITS
Current during SLEEP MODE	$ZZ \ge V$ IH	ISB2		TBD	mA
ZZ active to input ignored		tpds	2		cycle
ZZ inactive to input sampled		tpus	2		cycle
ZZ active to SLEEP current		tzzı		2	cycle
ZZ inactive to exit SLEEP current		trzzi	0		

SLEEP MODE WAVEFORM

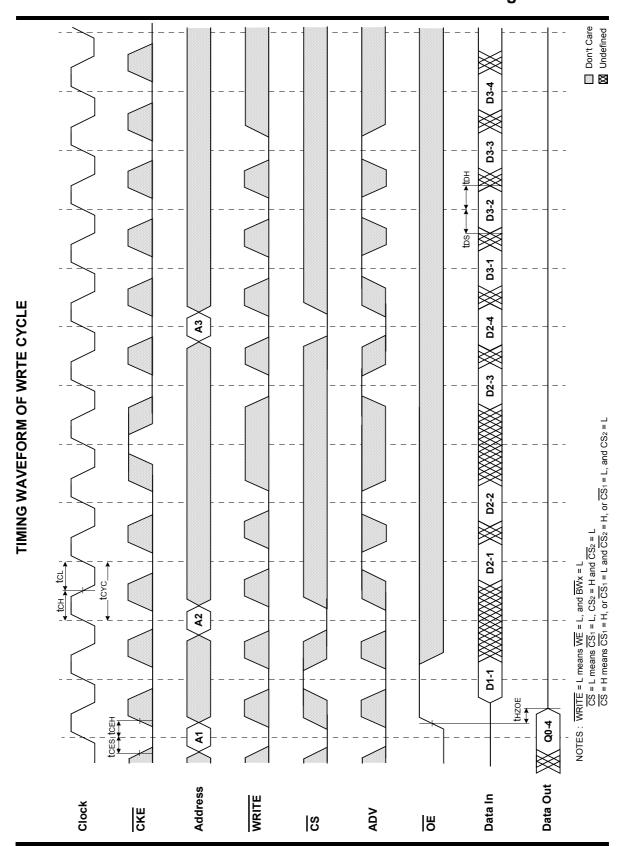




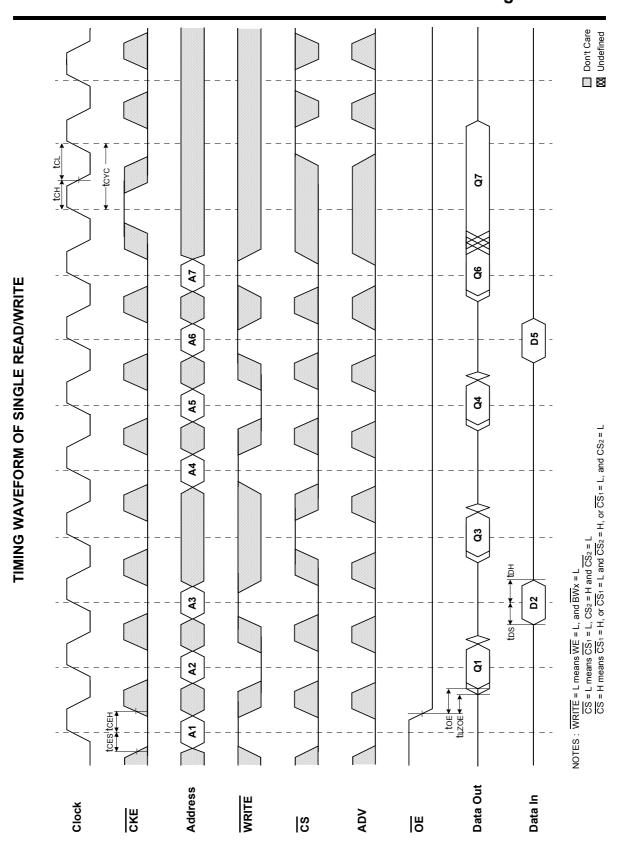




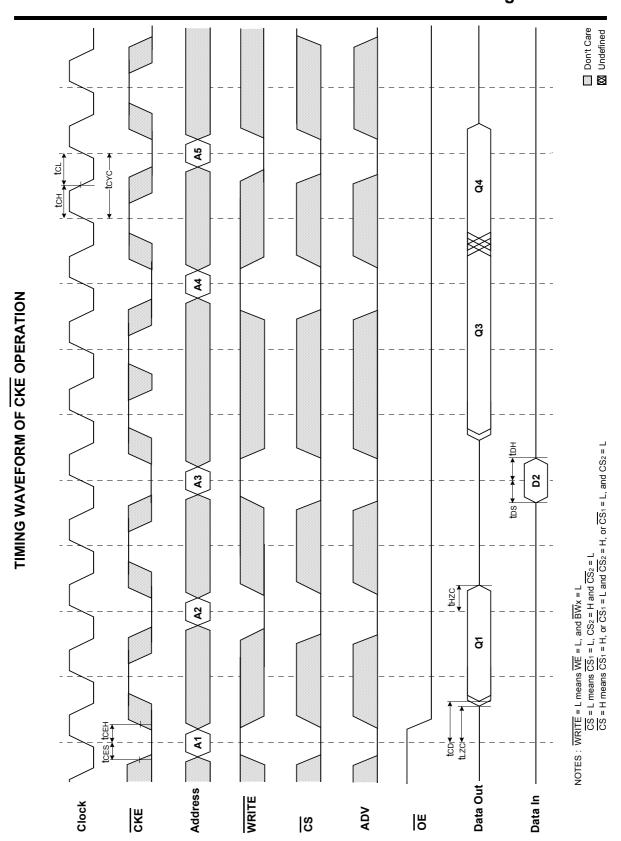




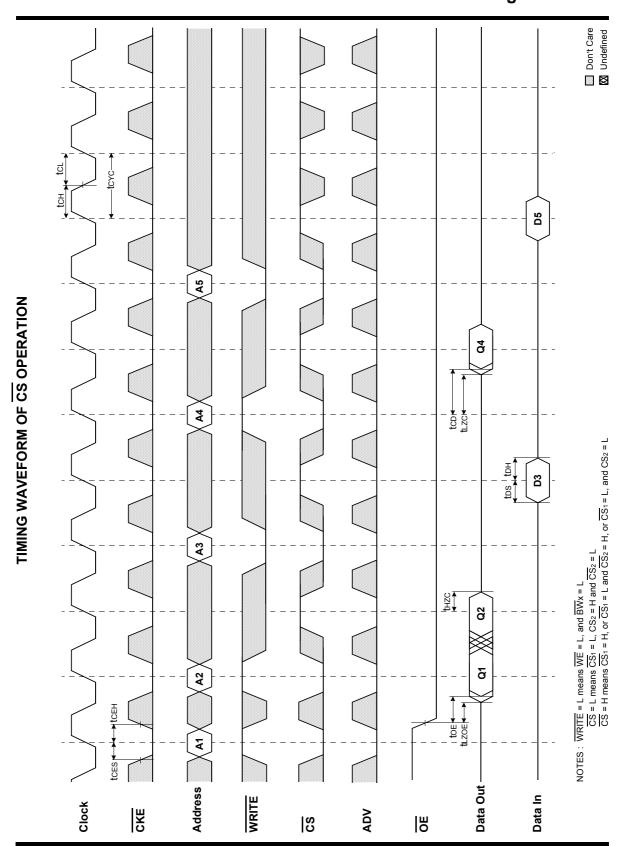














PACKAGE DIMENSIONS

